

FIG. 1

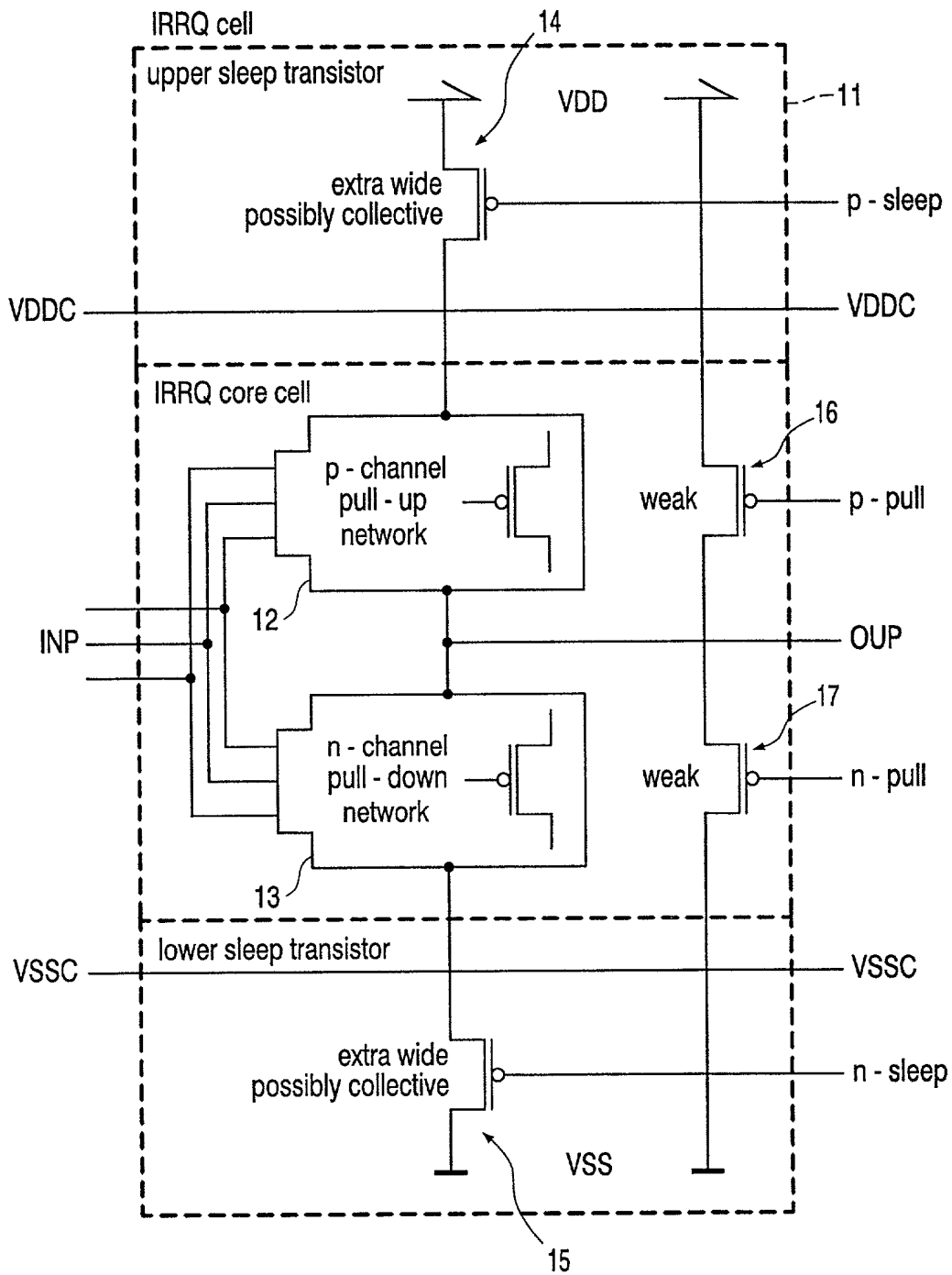


FIG. 2

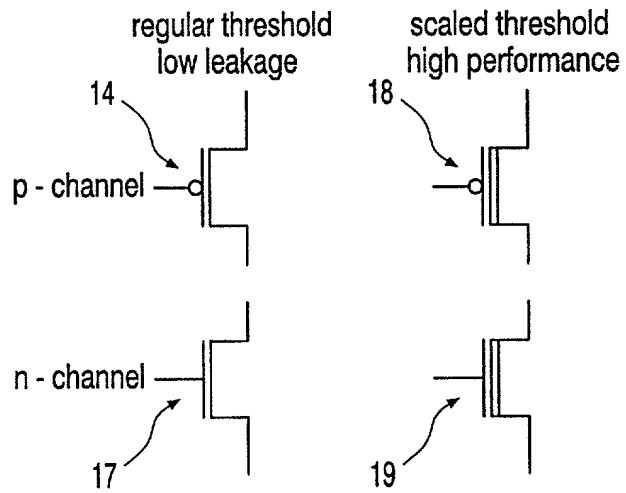


FIG. 3

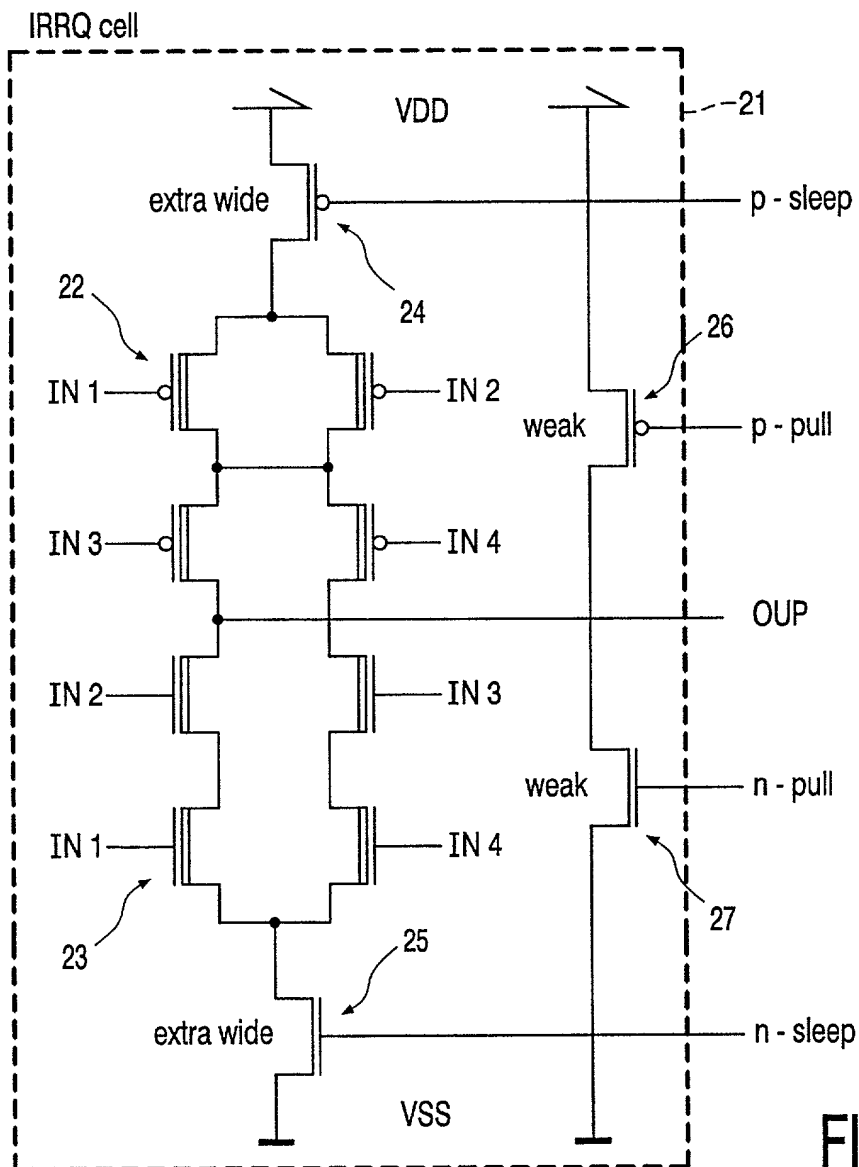


FIG. 4

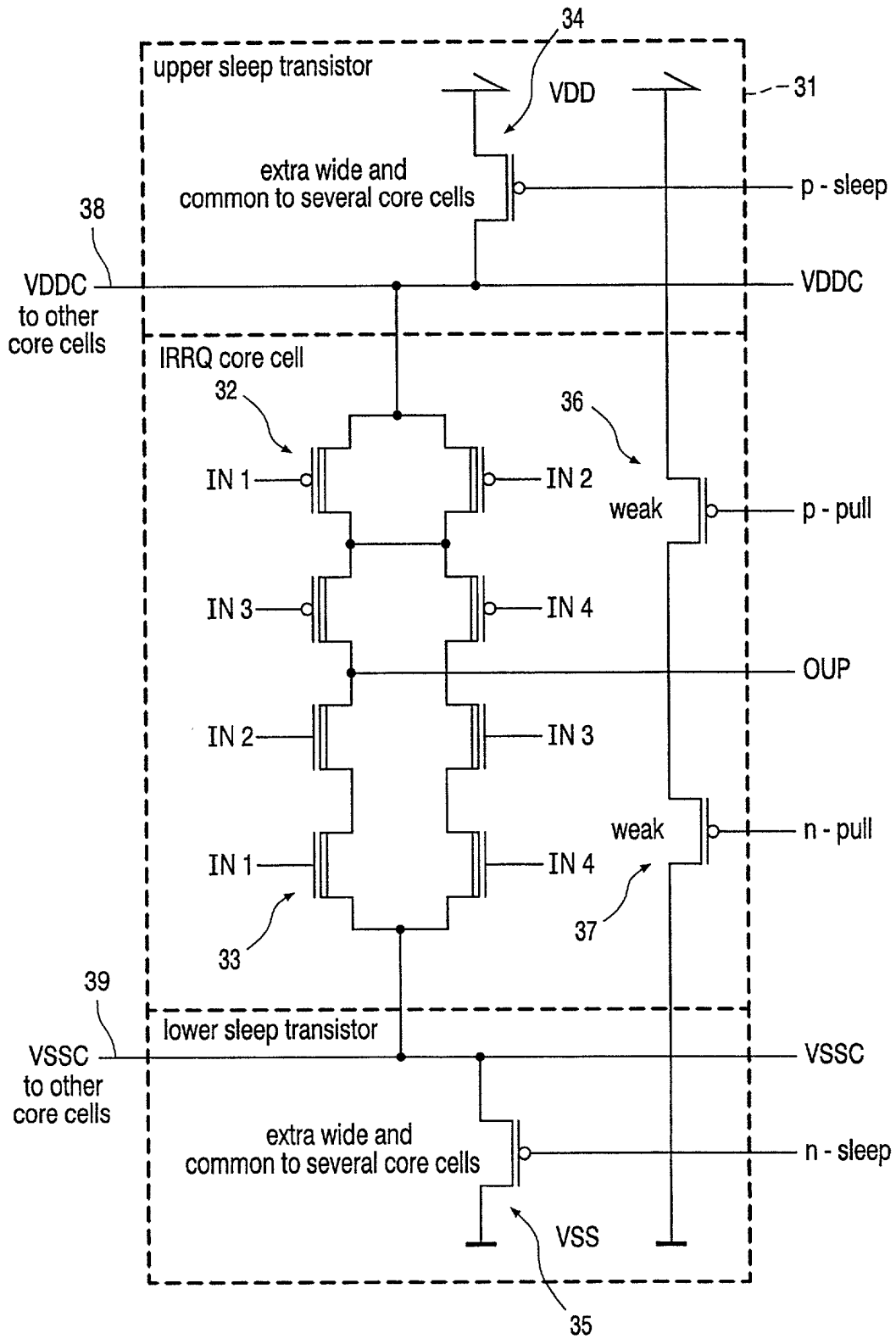


FIG. 5

defect to be checked	n - netw.	p - netw.	n - sleep	n - pull	p - pull	p - sleep	I _{ddq}
within regular n - and p - channel networks							
n - channel open or short	stimulate	don't care	on	off	on	off	
p - channel open or short	don't care	don't care stimulate	off	on	off	on	
within auxiliary transistors							
n - sleep open or short	on	don't care	toggle	off	on	off	
p - sleep open or short	don't care	on	off	on	off	toggle	
p - pull open	on	don't care	toggle	off	on	off	check idem
p - pull short	on	don't care	toggle	off	on	off	
p - pull on (weak pull - up)	on	don't care	on	off	off	off	
or alternatively	don't care	don't care	off	on	off	off	
n - pull open	don't care	on	off	on	off	toggle	check idem
n - pull short	don't care	on	off	on	off	toggle	
n - pull on (weak pull - dn)	don't care	on	off	off	off	on	
or alternatively	don't care	don't care	off	off	on	off	

FIG. 6

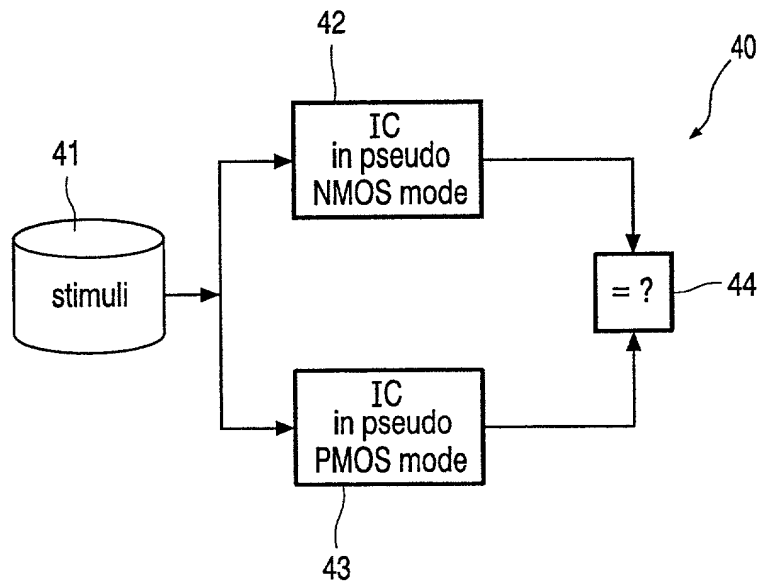


FIG. 7A

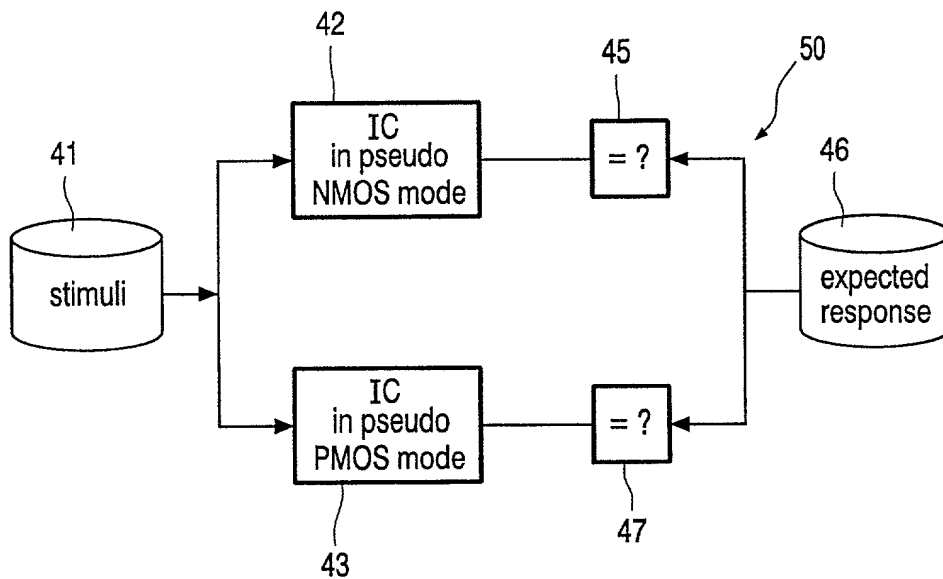


FIG. 7B